Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10552705	SHIBAYAMA ET AL.
Examiner	Art Unit
DAVID S BAKER	2884

SEARCHED					
Class	Subclass	Date	Examiner		
250	370.11	16 NOV 08	DSB		
250	371	16 NOV 08	DSB		

SEARCH NOTES		
Search Notes	Date	Examiner
See attached EAST Search History	16 NOV 08	DSB
Consultation: Examiner Christine Sung AU 2884	16 NOV 08	DSB

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
ALL	ALL; Search Terms: "(signal WITH process\$5).clm. AND (through WITH hole) AND shield\$5 AND (glass WITH substrate).clm."	16 NOV 08	DSB
250	ALL; Search Terms: "(signal WITH process\$5).clm. AND (through WITH hole) AND shield\$5 AND (glass WITH substrate).clm."	16 NOV 08	DSB
ALL	ALL; Search Terms: "(signal WITH process\$5).clm. AND (through WITH hole) AND (glass WITH substrate).clm."	16 NOV 08	DSB
250	ALL; Search Terms: "(signal WITH process\$5).clm. AND (through WITH hole) AND (glass WITH substrate).clm."	16 NOV 08	DSB
ALL	ALL; Search Terms: "(signal WITH process\$5).clm. AND (through WITH hole) AND shield\$5"	16 NOV 08	DSB
250	ALL; Search Terms: "(signal WITH process\$5).clm. AND (through WITH hole) AND shield\$5"	16 NOV 08	DSB

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